

Material sciences with high-brightness, low energy positron beams

MARCEL DICKMANN



Content

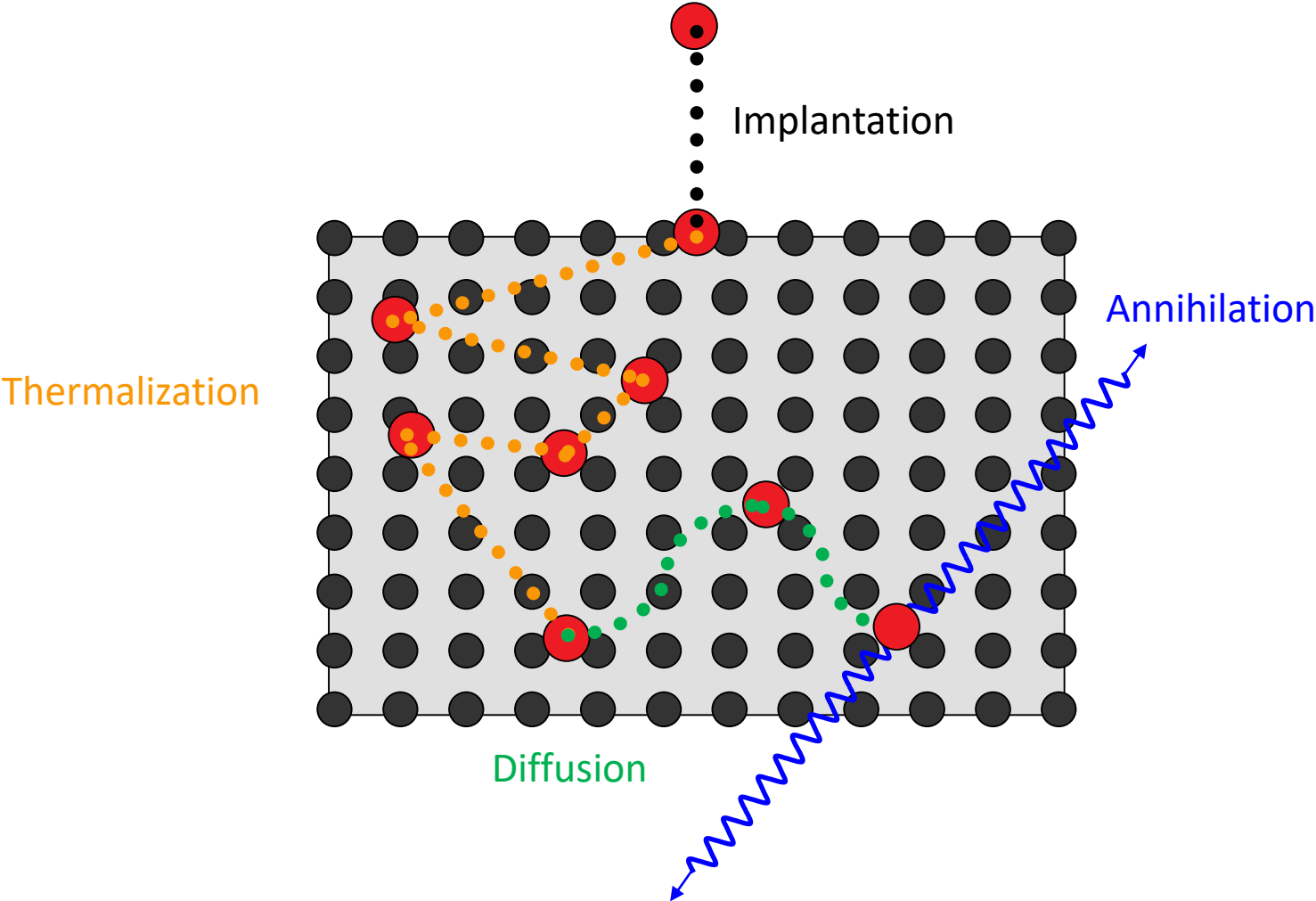
Principles of Positron (Lifetime) Spectroscopy

- Positrons in Matter
- Depth-resolved PALS
- Pulsed Positron Beams in Munich

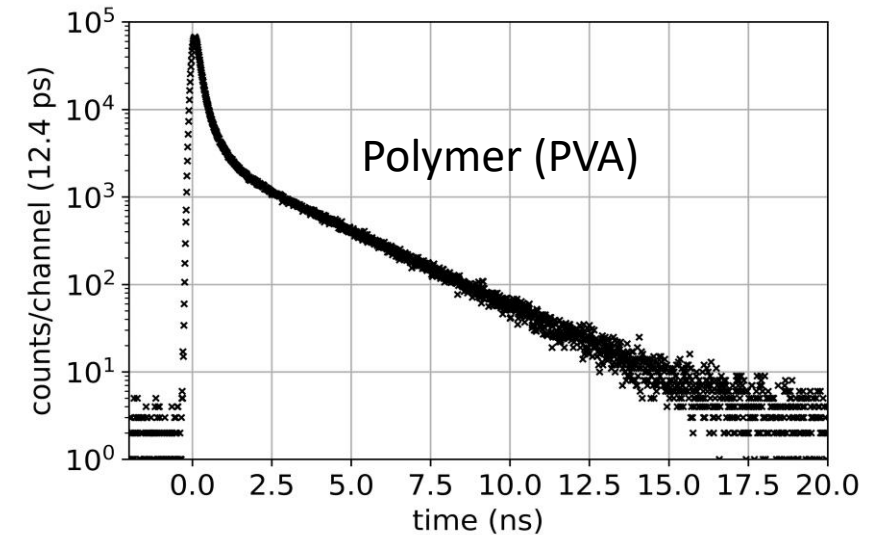
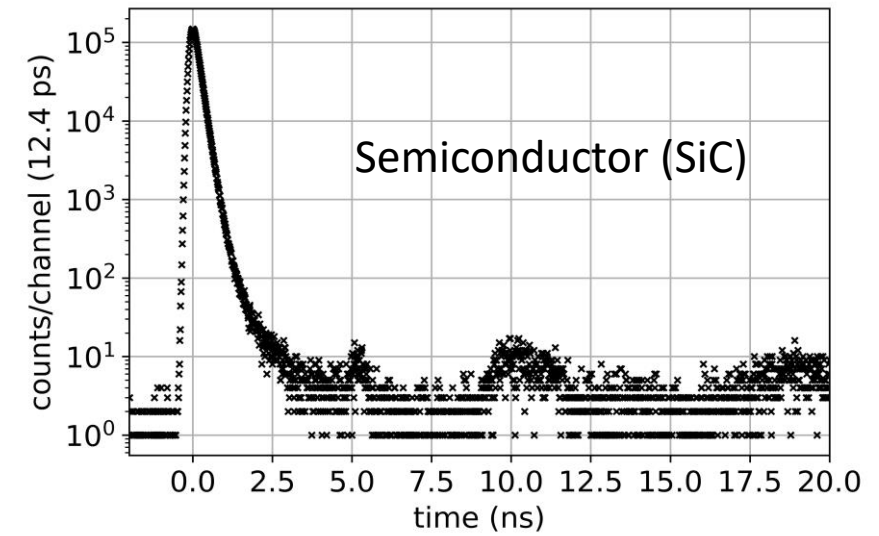
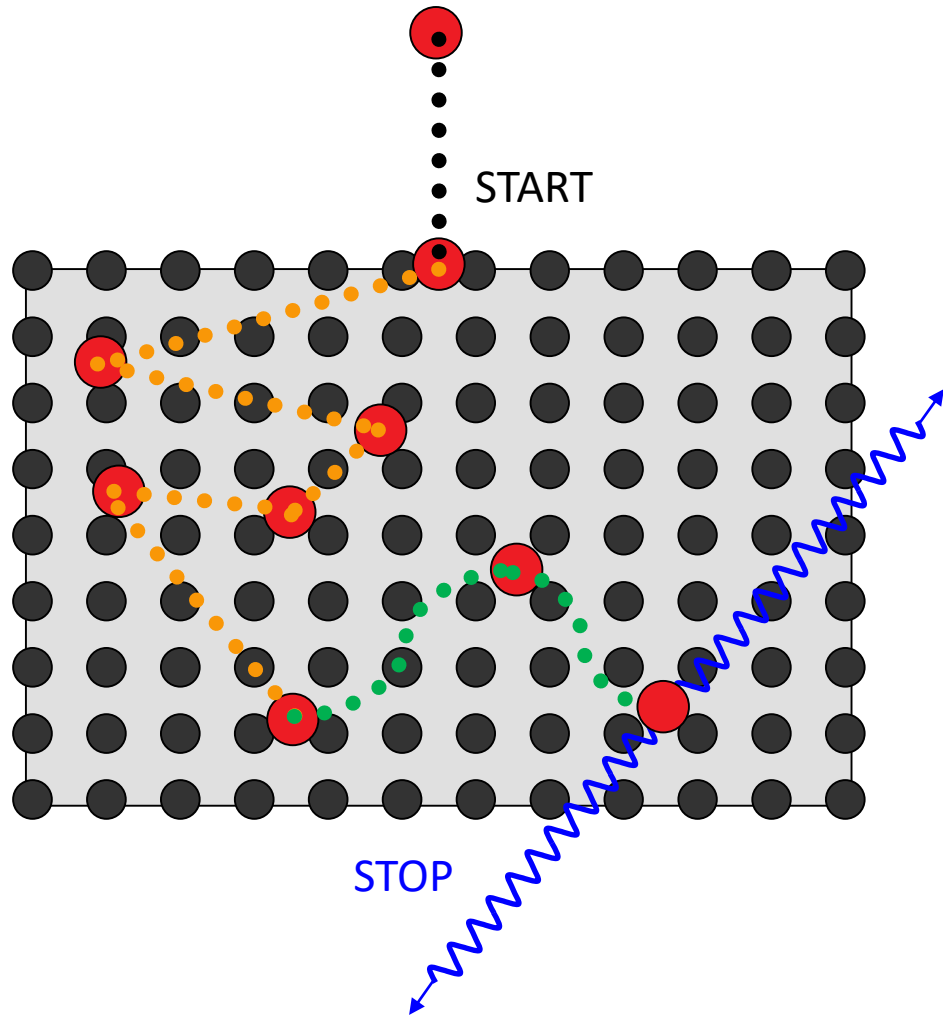
Selection of Investigated Materials using PALS

- NV Centers in Diamond
- Fusion Materials

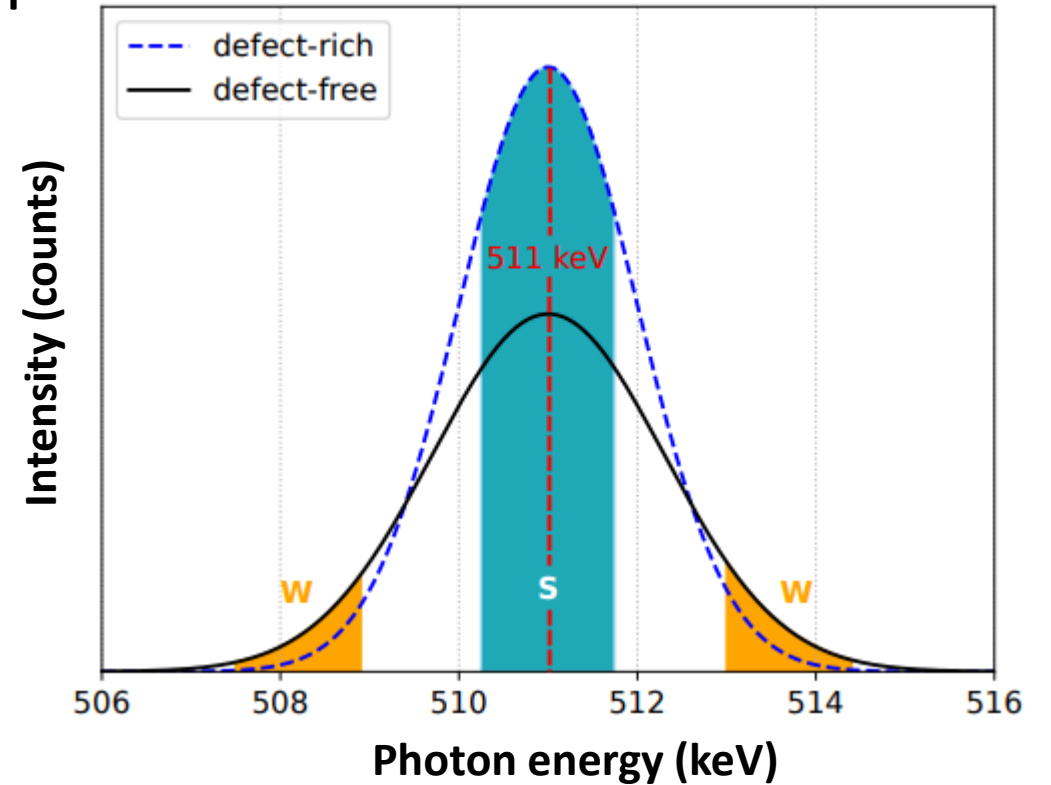
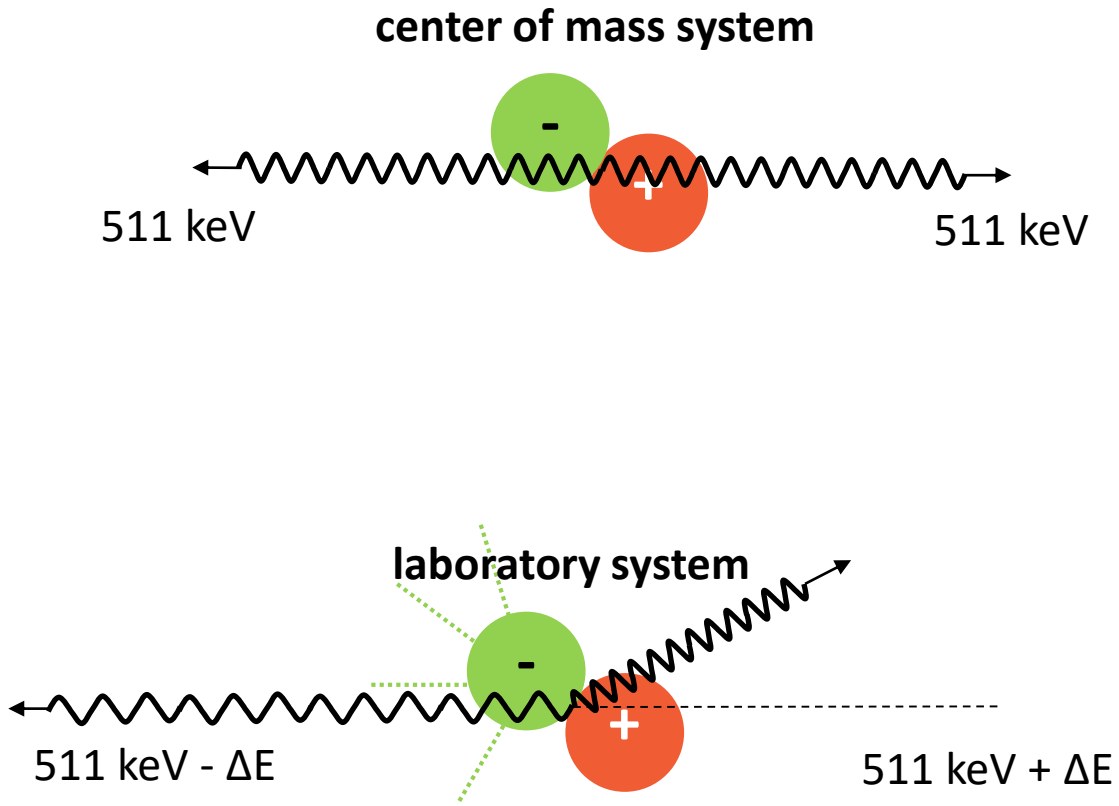
Implantation, Thermalization, Diffusion, Annihilation



Positron Annihilation Lifetime Spectroscopy



Doppler-Broadening Spectroscopy

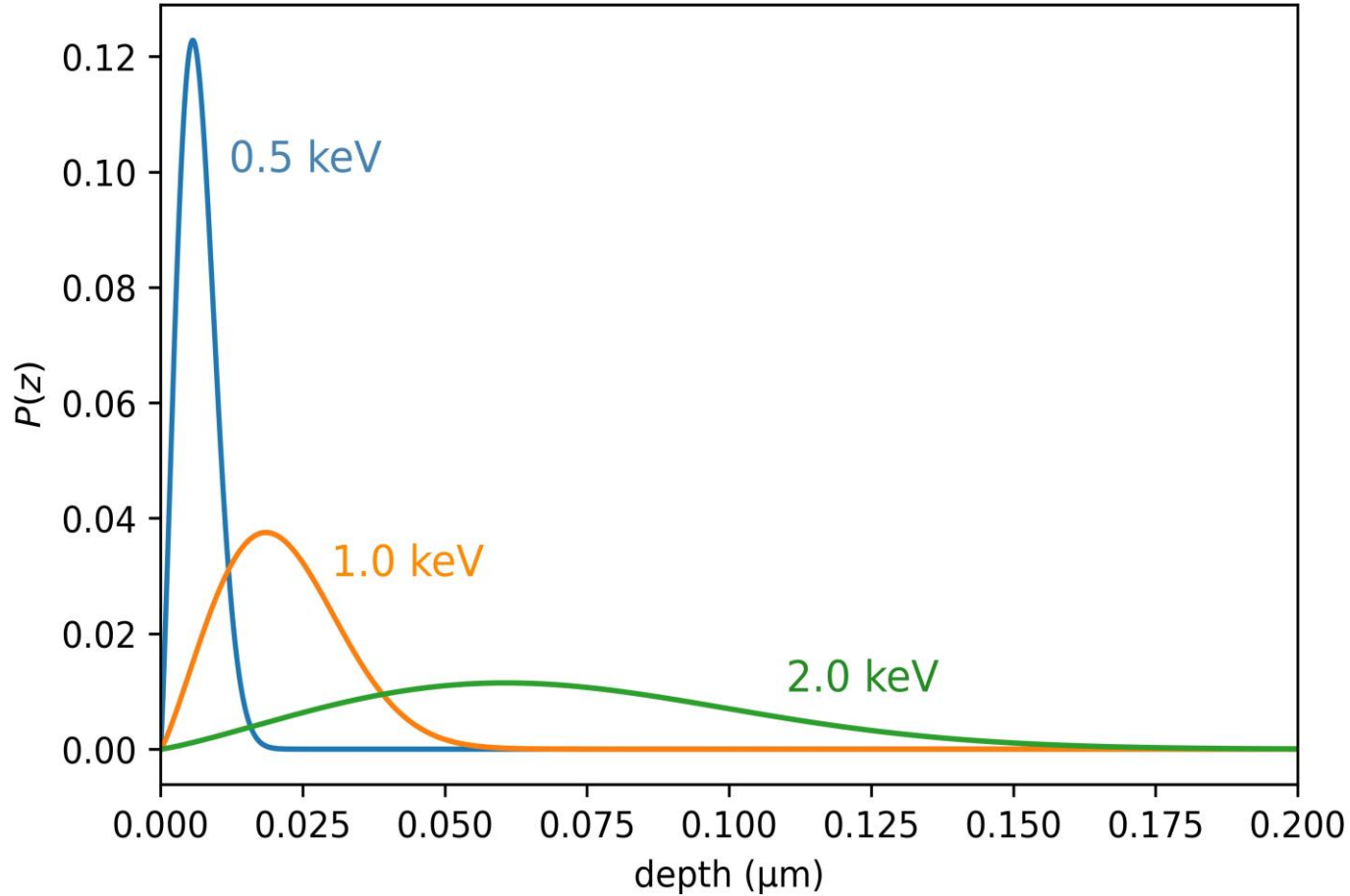


$$S = \frac{\text{[Cyan Area]}}{\text{whole area}}$$

$$W = \frac{\text{[Orange Area]}}{\text{whole area}}$$

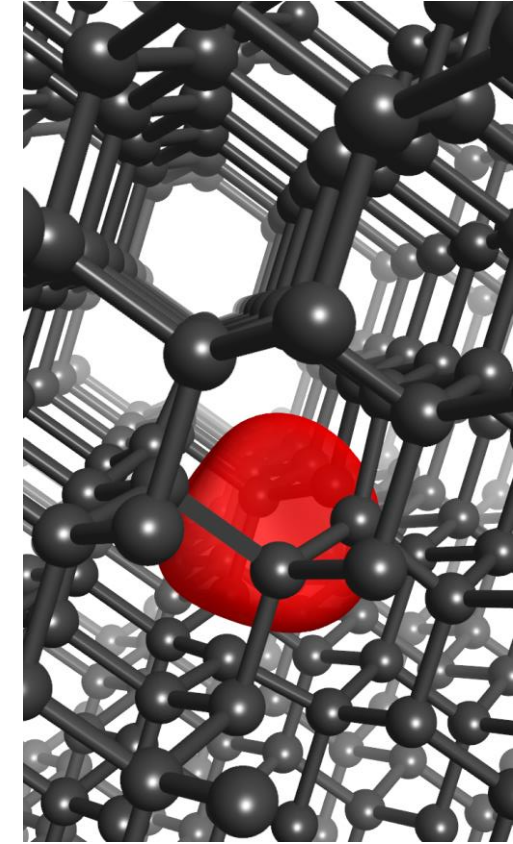
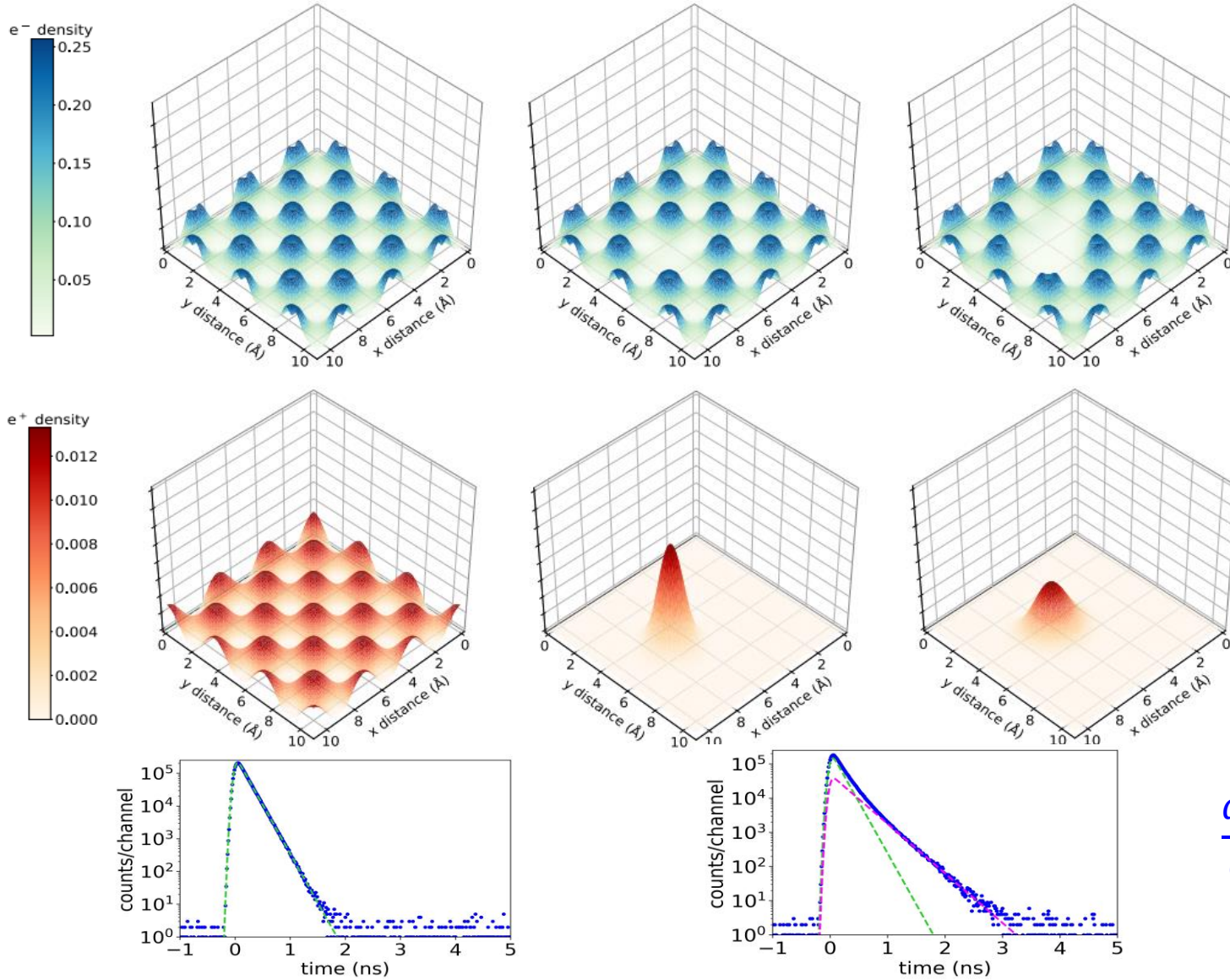
Positron Implantation

Positron implantation profiles using a mono-energetic beam



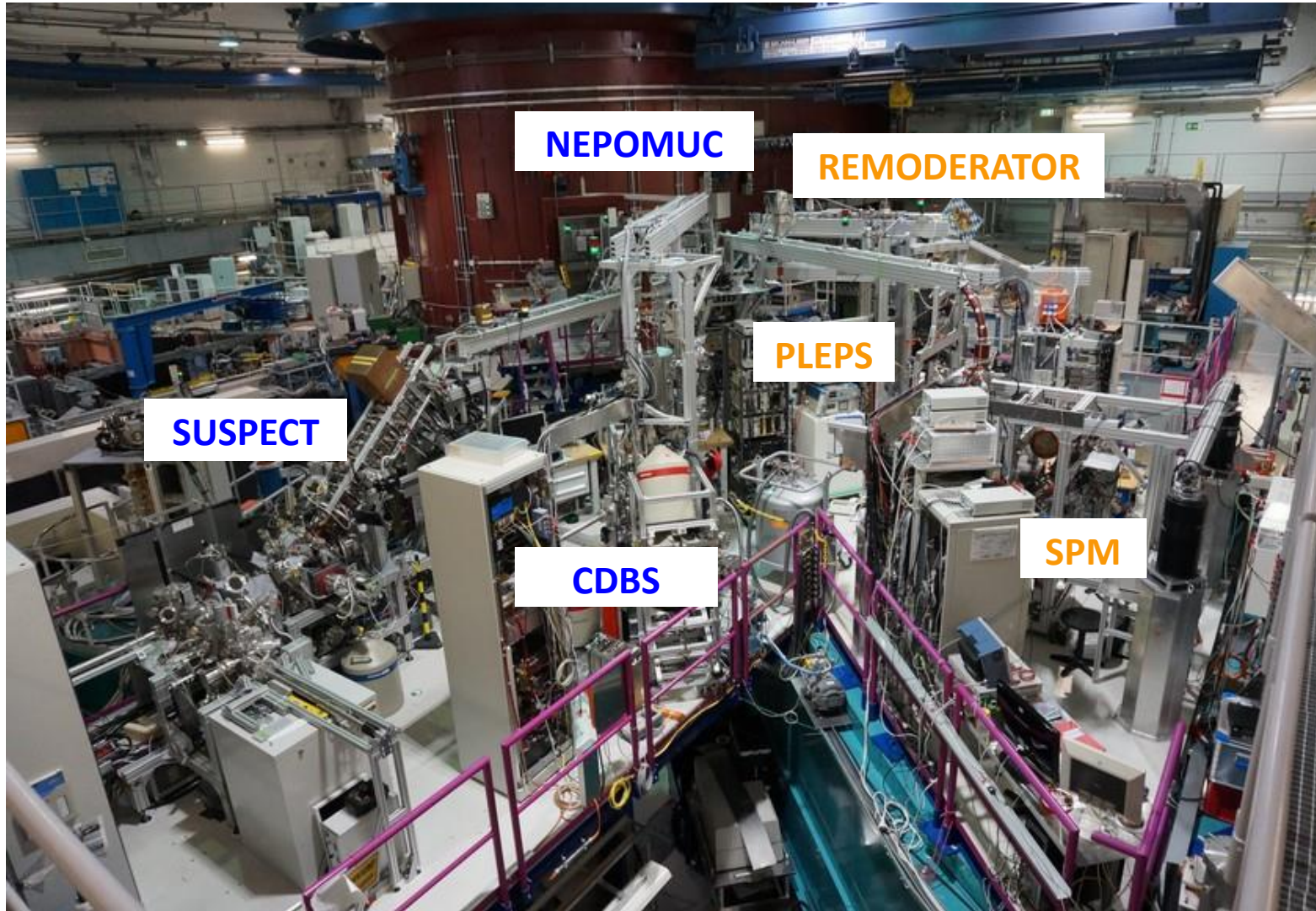
Material	density (g/cm ³)	mean implantation depth (μm)	
		@4keV	@20keV
PMMA	1.09	0.250	3.94
Quartz	2.65	0.102	1.78
Aluminum	2.70	0.106	1.76
Copper	8.96	0.032	0.468
Lead	11.3	0.045	0.407
Tungsten	19.3	0.021	0.230

Positrons in Matter



$$\frac{dN}{dt}(t) = \sum_{i=1}^n \frac{I_i}{\tau_i} \cdot e^{-t/\tau_i}$$

Experimental Hall of the FRM II



NEPOMUC

NEutron-induced Positronsource MUniC

SUSPECT

SurfaceSPECTrometer

CDBS

Coincidence Doppler Broadening Spectrometer

PLEPS

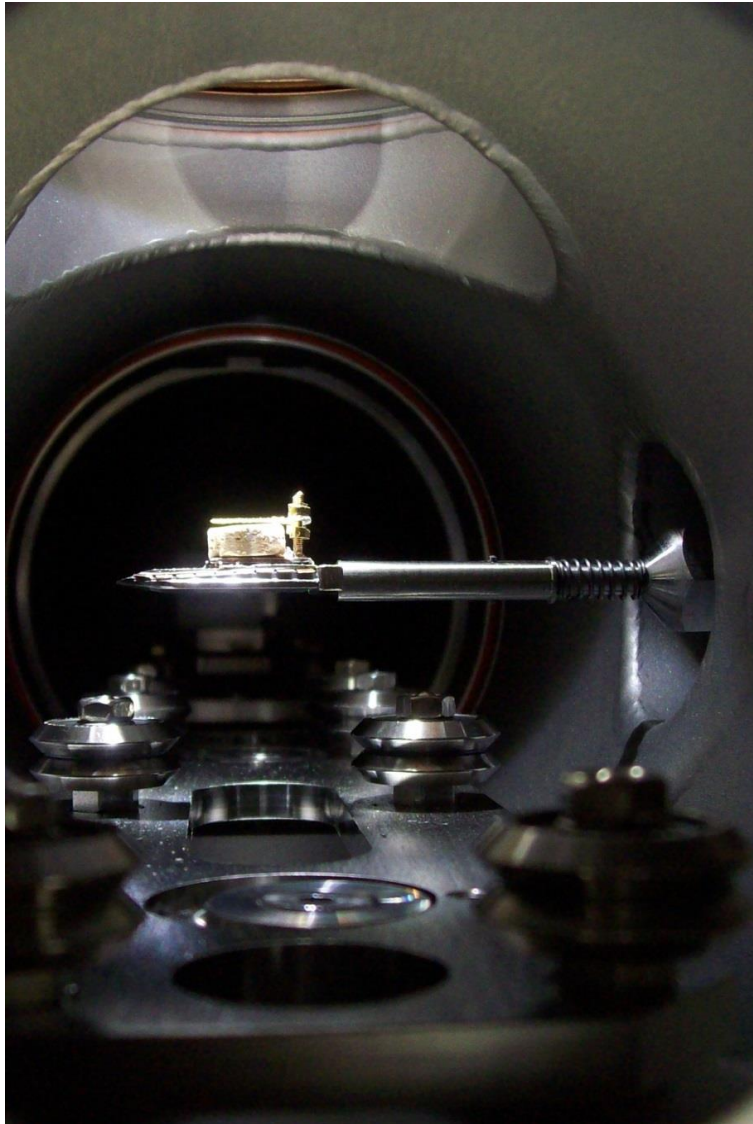
Pulsed Low-energy Positron System

SPM

Scanning Positron Microscope

REMODERATOR

The Pulsed Beam System PLEPS



Implantation Energy

0.25 – 20 keV

Beam Diameter

< 1mm

Total Time Resolution

180 ps (FWHM)

Measurement Time per Spectrum

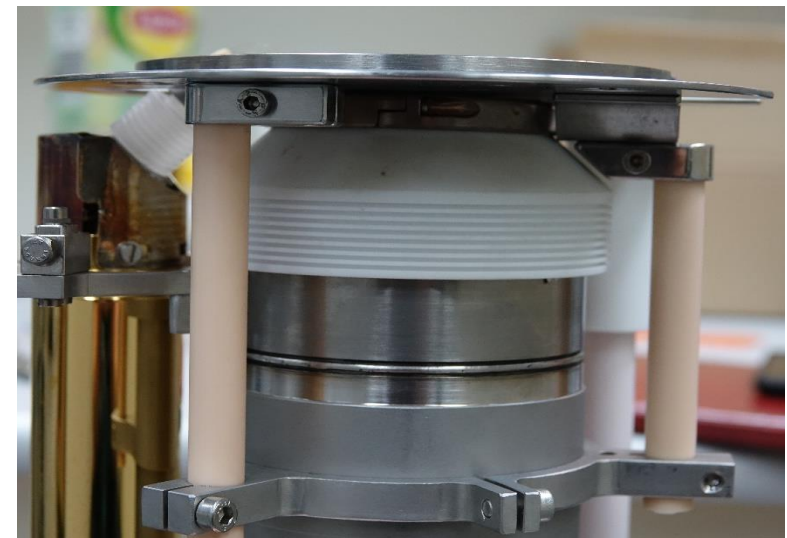
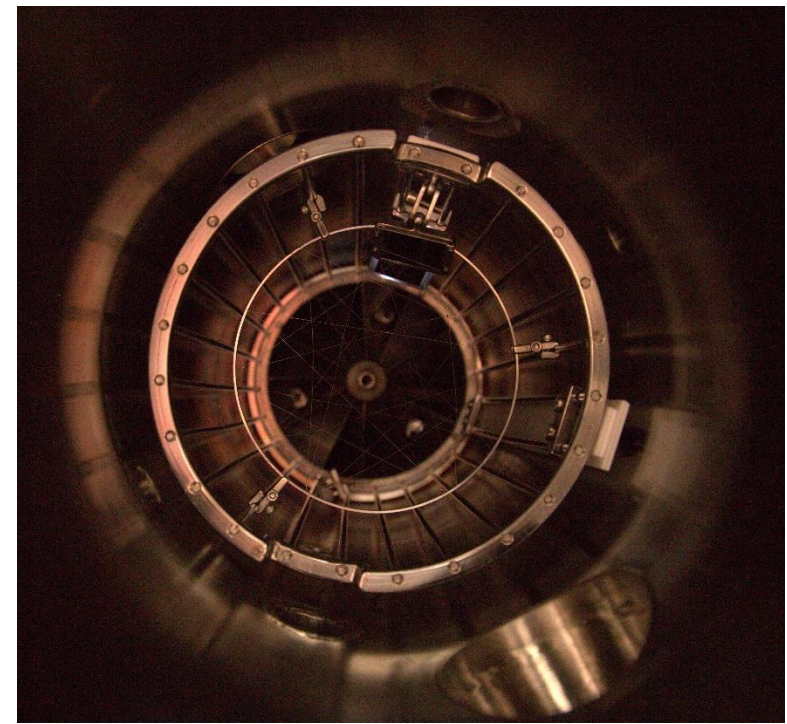
10 min (4 Mio. Events)

Sample Temperature

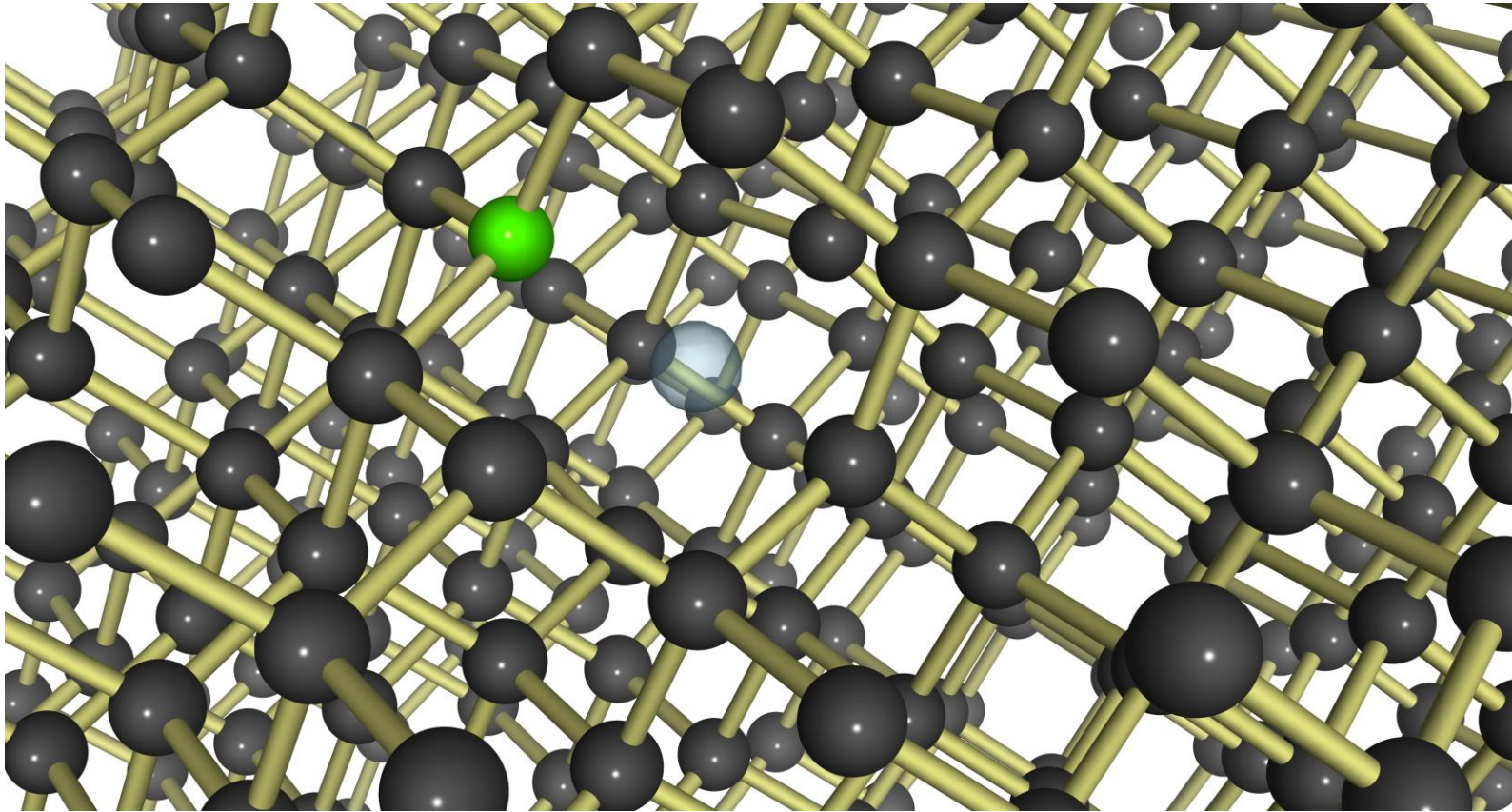
80 – 600 K

***In Situ* Light illumination**

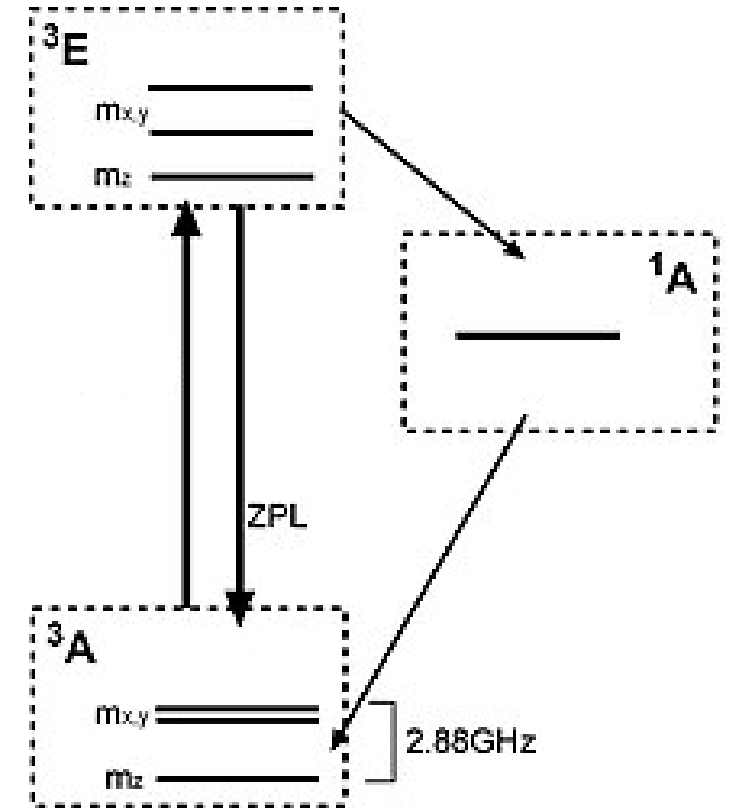
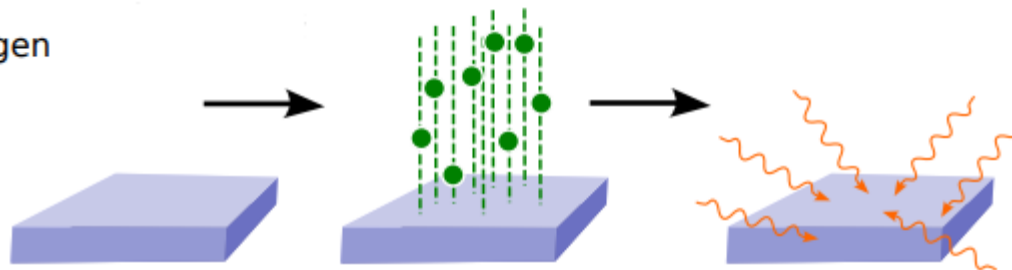
200 – 2000 nm



NV Centers in Diamond

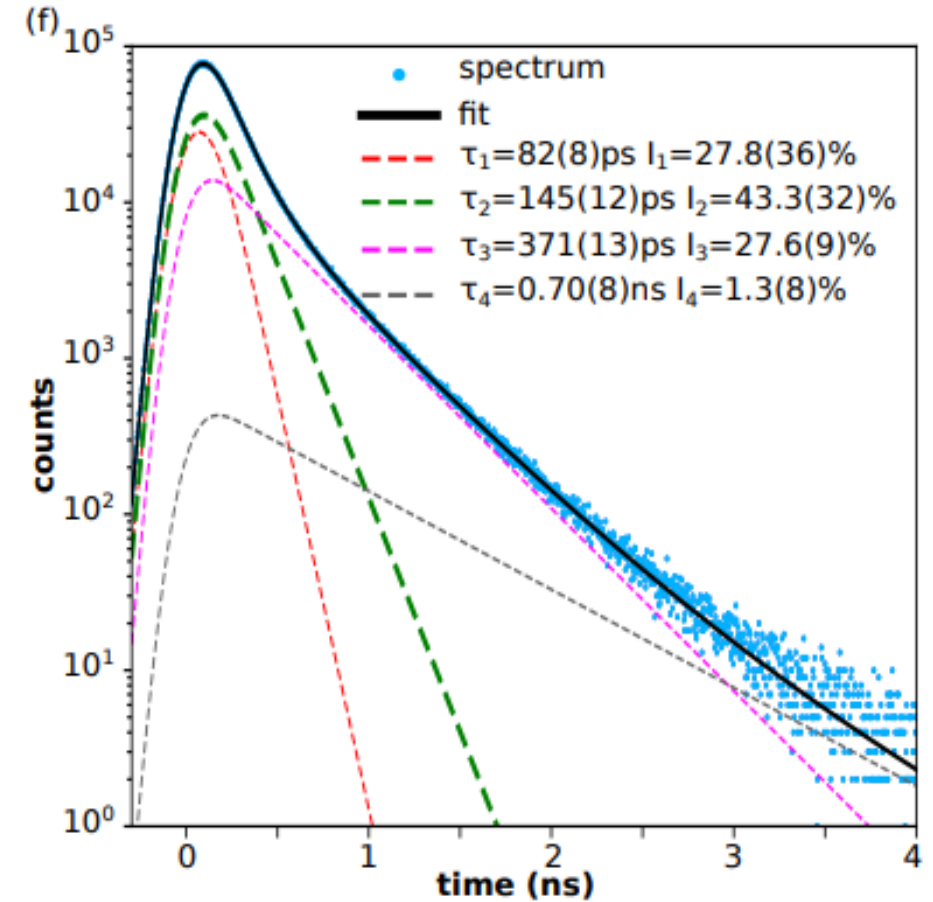
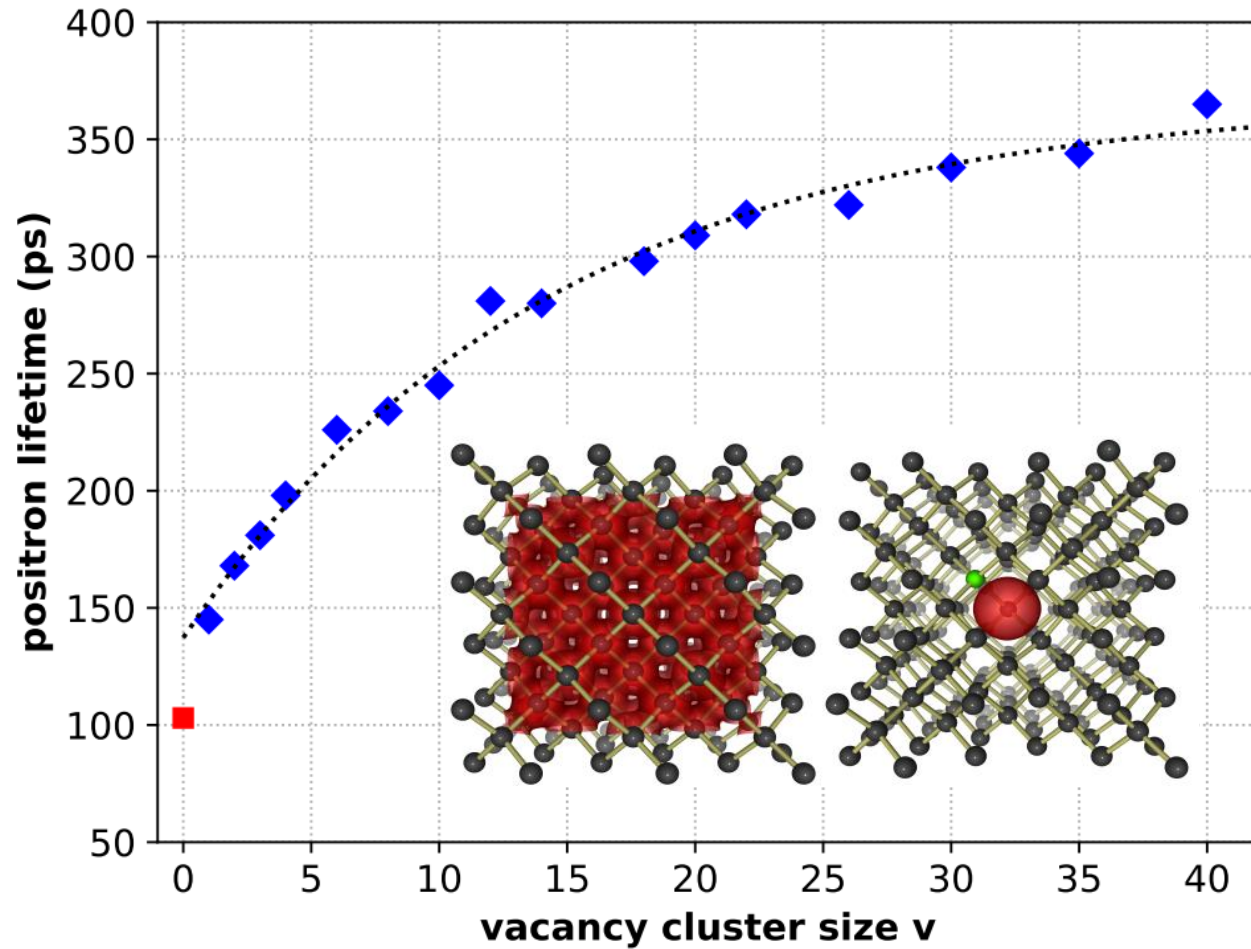


● carbon ● nitrogen

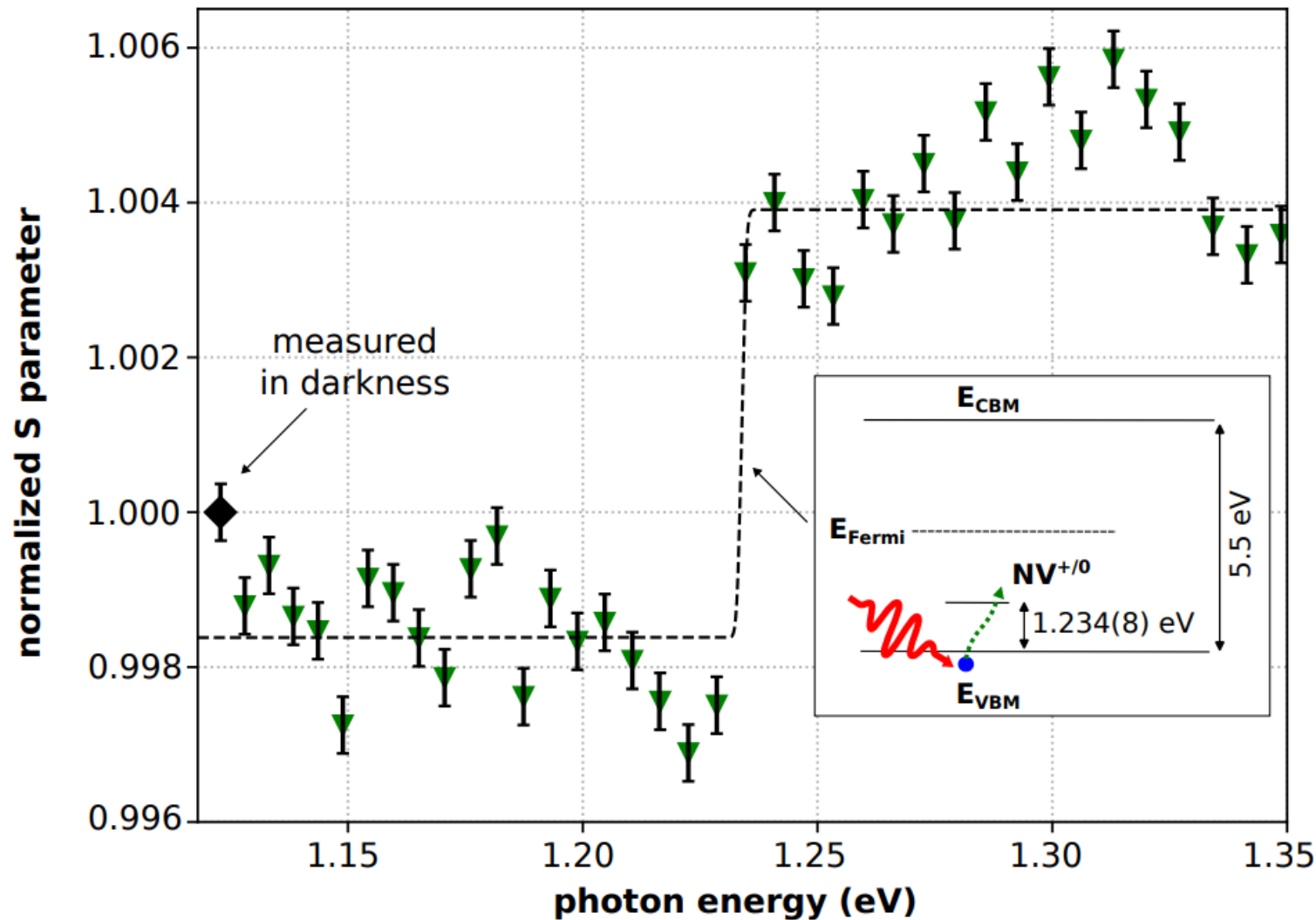


Possible charge states:
 NV^0 , NV^- and NV^+

Defects in Diamond revealed by PALS



S-parameter with *in situ* light illumination

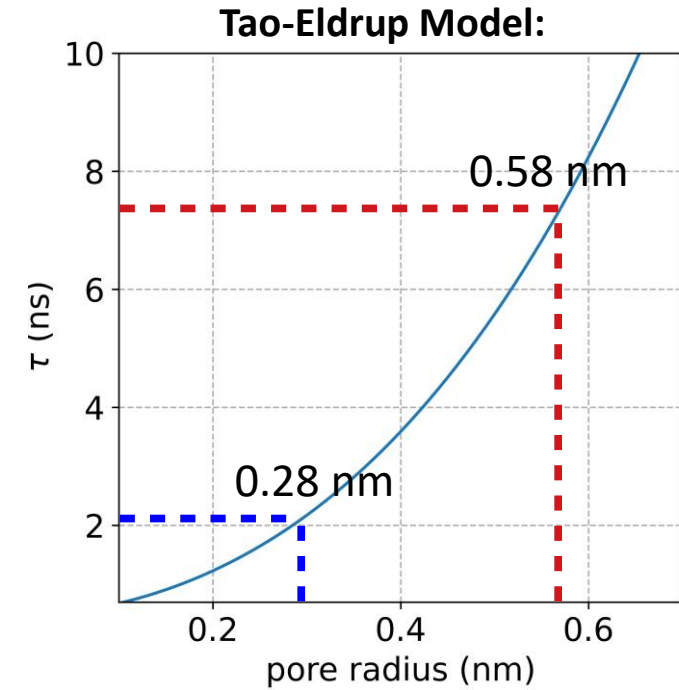
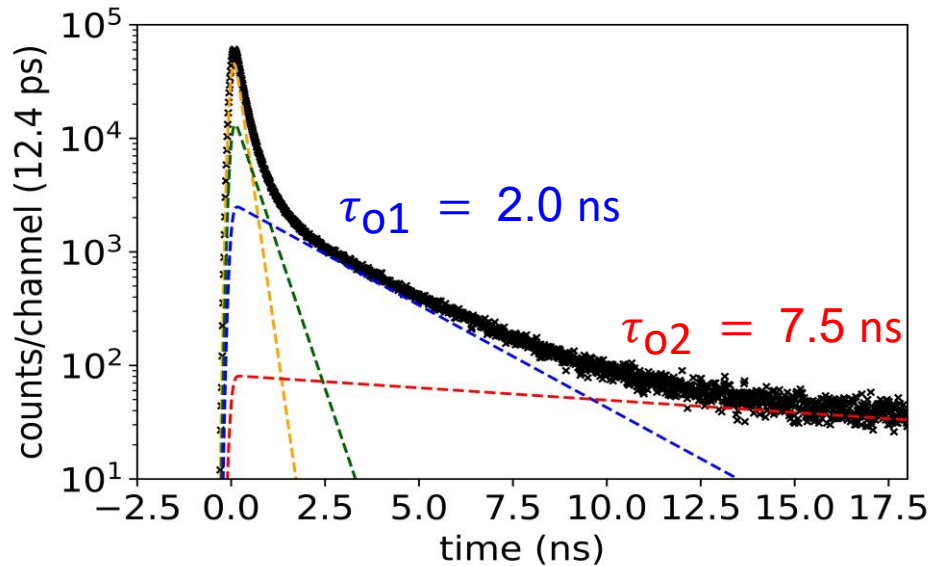
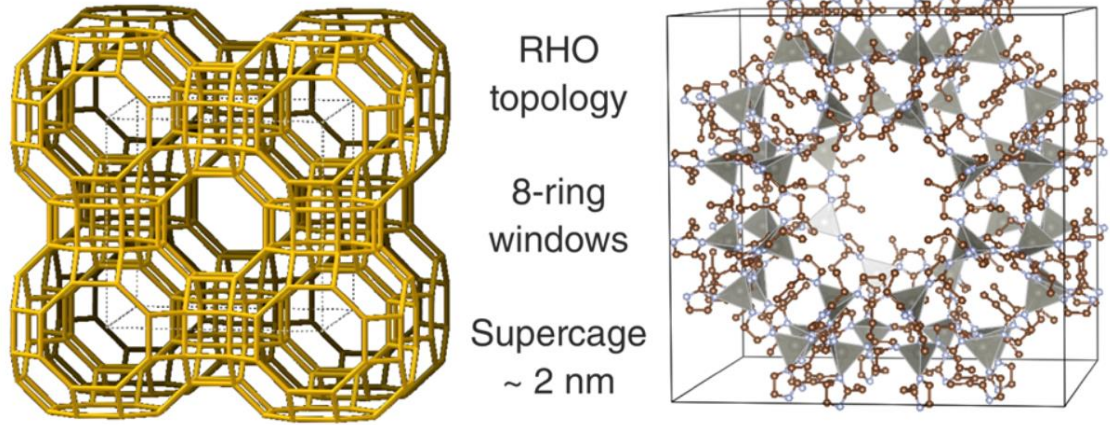


Measurement parameters

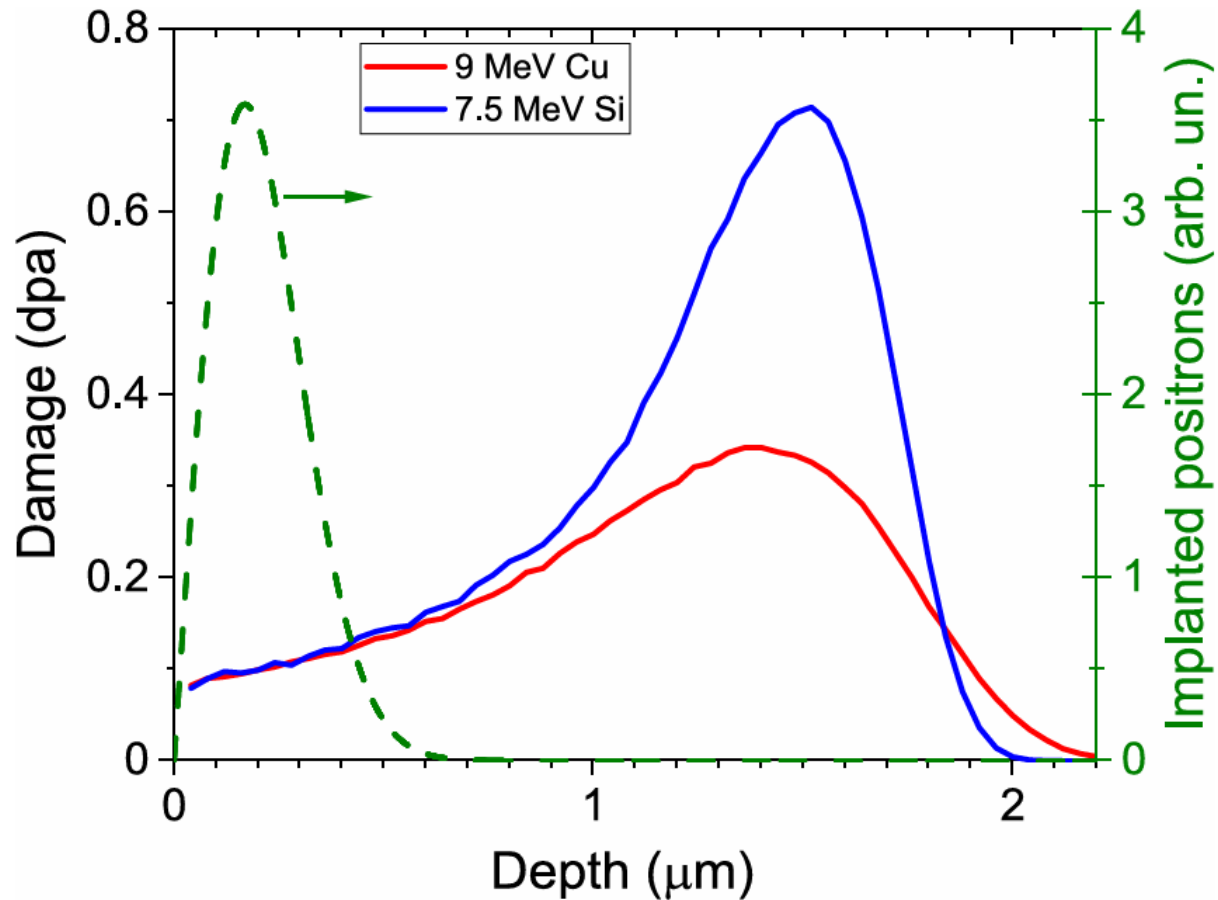
- Mono-chromatic light $\Delta\lambda = 6$ nm
- Room temperature
- Stored for > 10 h in complete darkness
- First proof of evidence for NV^{+} centers next to NV^0 and NV^{-}
- Paper currently under review

Porosimetry of Polymers

T. Stassin et al. *Advanced Materials* 2009662:
(2021)



Damage caused by heavy ions

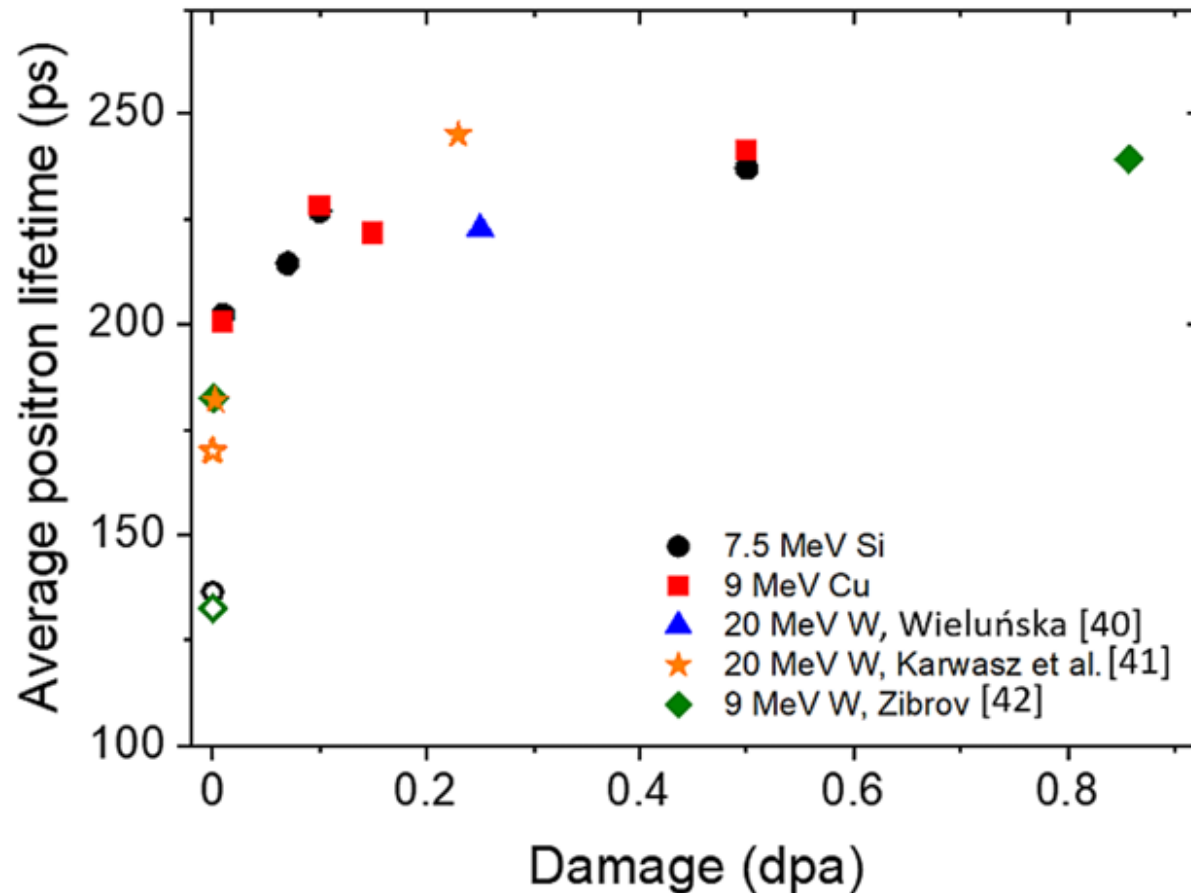


Experimental Goals:

- Irradiation-induced vacancy formation in tungsten
- Imitation of neutron-induced damage by heavy ions
- Comparison between Cu and Si ions
- Comparison between different damage levels (dpa)

B. Wieluńska-Kuś, M. Dickmann, W. Egger, M. Zibrov, L. Ciupinski, "Positron lifetime study of ion-irradiated tungsten: Ion type and dose effects." Nuclear Materials and Energy 38 (2024): 101610.

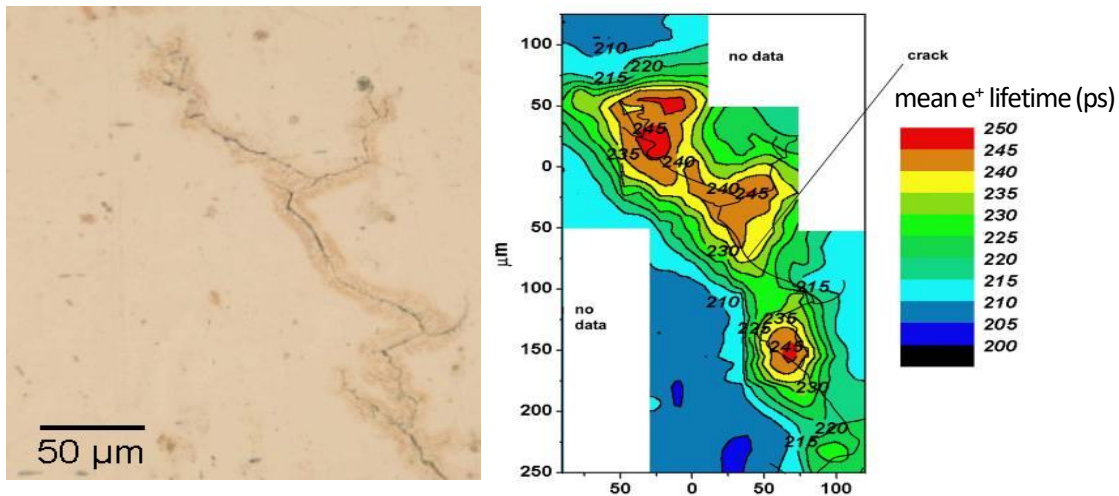
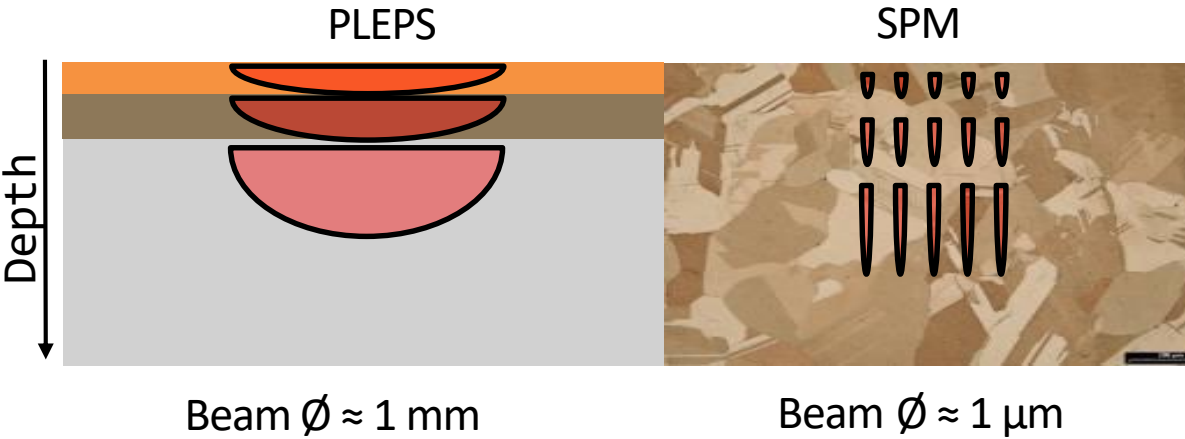
Comparison with previous results



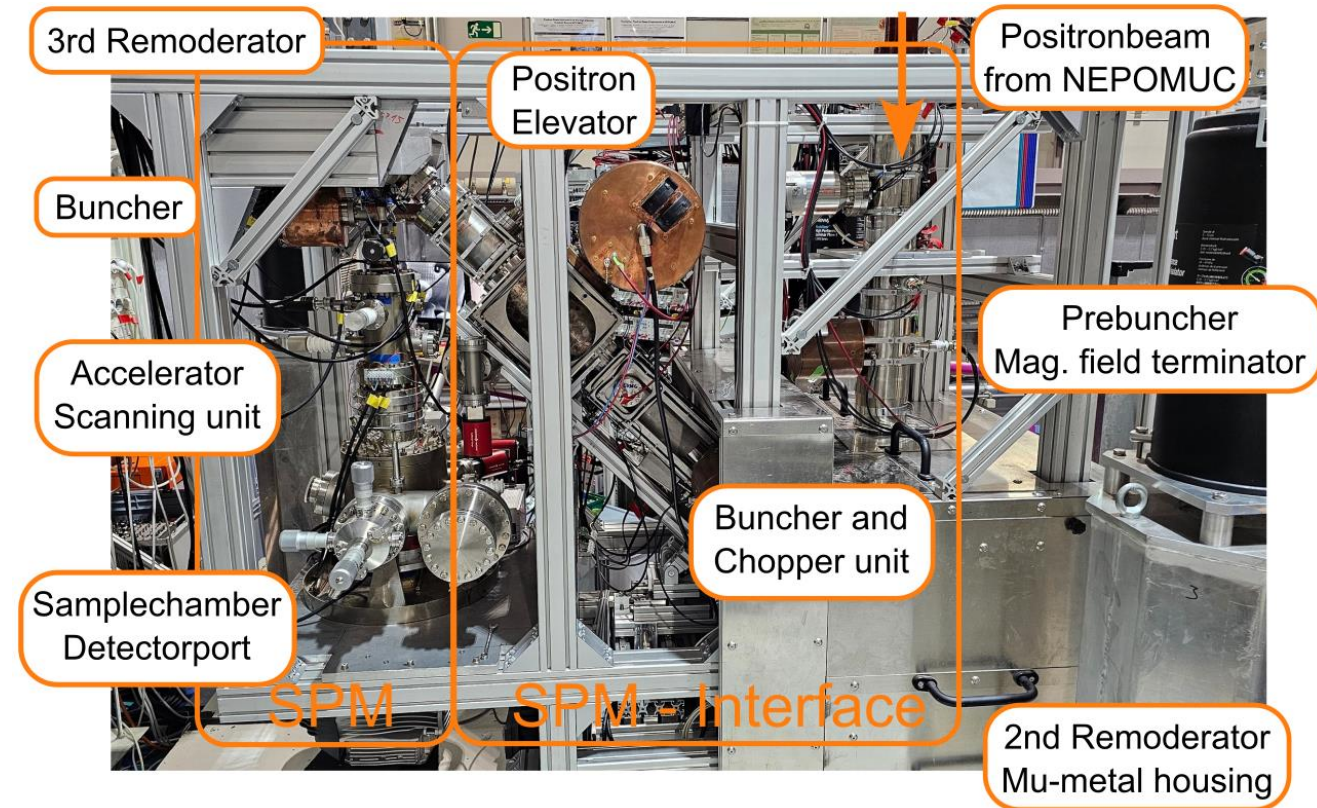
- The average positron lifetime increases non-linearly with damage level, showing a rapid increase at lower damage levels with saturation above 0.1 dpa.
- Both Si and Cu irradiation produced similar vacancy-type defect structures, with predominantly single vacancies at low damage levels and a growing presence of small vacancy clusters at higher levels.
- The results support previous studies and molecular dynamics simulations, suggesting that the defect concentration tends to stabilize at higher damage levels.

B. Wieluńska-Kuś, M. Dickmann, W. Egger, M. Zibrov, L. Ciupinski, "Positron lifetime study of ion-irradiated tungsten: Ion type and dose effects." *Nuclear Materials and Energy* 38 (2024): 101610.

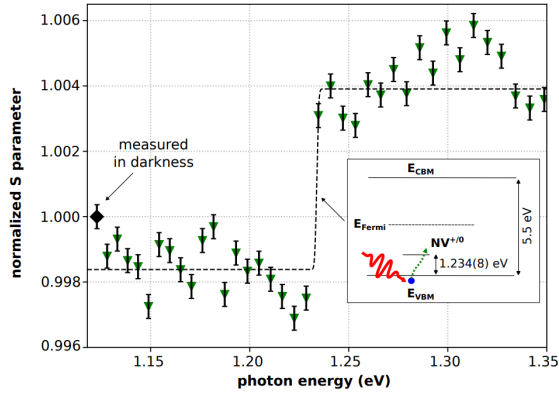
The Scanning Positron Microscope (SPM)



W. Egger, G. Kögel, P. Sperr, W. Triftshäuser, J. Bär, S. Rödling, H.-J. Gudladt *Applied Surface Science* 194 (1): 214 - 217 (2002)



SUMMARY



- Positrons are ideal probes for open-volume defects
- Positron annihilation spectroscopy gives information on defect types and their concentration
- Wide range of applications in material sciences (e.g. semiconductors, metals, polymers, quantum materials, ...)

